

Atomic Force Microscopy-Based Electrical Characterization of Materials

This timely book introduces the fundamental measurement concepts of the rapidly evolving atomic force microscopy (AFM) techniques for electrical characterization (EFM). It describes experimental approaches and setups, as well as challenges to overcome, and it also provides a wide range of real-world examples illustrating the method. This comprehensive guide for EFM techniques and their applications is an excellent reference for those working on microscopy in different fields, making the methods more accessible to a wider audience and enabling readers to explore the numerous possibilities of electrical techniques as research tools.



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